## Electronic Structure Study of CaCu<sub>3</sub>Ti<sub>4</sub>O<sub>12</sub> by means of Soft X-ray Raman Scattering

Seiya Nakamoto<sup>1\*</sup>, Kenjiro Nishiyama<sup>1</sup>, Hojun Im<sup>1</sup>, Takao Watanabe<sup>1</sup>,

Nobuo Nakajima<sup>2</sup>, and Yasuhisa Tezuka<sup>1\*</sup>

<sup>1</sup>Grad. Sch. of Sci. and Tech., Hirosaki Univ., Hirosaki, Aomori 036-8561, Japan <sup>2</sup>Grad. Sch. of Sci., Hiroshima Univ., Higashi-Hiroshima, Hiroshima 739-8526, Japan

## 1 Introduction

A-site ordered perovskite CaCu<sub>3</sub>Ti<sub>4</sub>O<sub>12</sub> (CCTO) has attached much attention recently, because it shows a giant dielectric constant ( $\sim 10^5$ ) over wide temperature range from about 100 to 600 K and the dielectric constant decreases to one-hundredth without structural phase transition at the temperature under about 100 K [1]. To clarify the nature of the anomalous dielectrics, it is important to investigate electronic structure of CCTO. Since X-ray Raman scattering (XRS) uses photons in both excitation and detection, it is effective in the study of electronic state of insulator materials. The results of XRS on Cu K edge showing excitation of Cu 2p3d and 2p4d, where underline denote core hole, have been reported [2]. On the other hand, it was suggested that band gap of CCTO is about 1.8 eV by Im et al. using photoemission and inverse photoemission spectroscopy [3], but it has not been confirmed yet. In this study, Cu L resonant XRS spectra of CCTO were observed to clarify the band gap.

## 2 Experiment

Single crystal CCTO(100) made by floating zone method was used in this study. XRS spectra were observed using soft X-ray emission spectrometer at beamline BL-16A. Vertically polarized light was used and scattering spectra in polarized configuration [4] were observed. The energy resolution of XRS measurement was about 1.0 eV.

## 3 Results and Discussion

Figure 1 shows Cu 2*p* XAS of CCTO measured by total electron yield method. The main structure is caused by Cu  $2p \rightarrow 3d$  transition and spin-orbit splitting of Cu 2*p* state was observed ( $L_{III}$  and  $L_{II}$ ). The XAS is very similar to that of divalent Cu-compounds such as CuO. Vertical bars with numbers denote excitation energies in XRS measurement.

Figure 2 shows Cu 2p resonant XRS spectra of CCTO. Several XES spectra excited around Cu 2p absorption edge are plotted against energy-loss from each excitation (Raman shift). Number beside each spectrum corresponds to that in Fig.1. Dots show observed spectra and vertical bars denote Cu  $L\alpha$  fluorescence peak. Solid lines in spectrum 2 are curve-fitting result by Gaussian function. The peak at 0 eV is an elastic peak, while an another peak is Raman peak. The Raman peak would be originated from *dd* excitation and has energy of about 1.8 eV. This result is in consistent with the band gap suggested by Im *et al.* 



Fig. 1: Cu 2p XAS of CCTO by total electron yield method. Vertical bars with numbers denote excitation energies in XRS measurement.



Fig. 2: Cu 2*p* resonant XRS spectra of CCTO. Dots show observed spectra and solid lines are curve-fitting result by Gaussian function.

References

- A.P. Ramirez, et al., Solid State Commun. 115, 217 (2000).
- [2] Y. Tezuka, et al., PF Activity Report #31, 323 (2014).
- [3] H. J. Im, et al., Solid State Commun. 217, 17, (2015).
- [4] Y. Harada, et al., J. Synchrotron Rad. 5, 1013 (1998).
- \* h15ms216@hirosaki-u.ac.jp
- \*\* tezuka@hirosaki-u.ac.jp